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PATENT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

INVENTOR: Christopher P. Ausschnitt) EXAMINER:
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SERIAL NO.:) ART UNIT:
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)
FILING DATE:) DATE: November 30, 2000
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FOR:))
 FOCUS CONTROL SYSTEM)

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

In accordance with 37 CFR 1.56, 1.97 and 1.98, the following items are made of record to assist the Patent & Trademark Office in its examination of this application and is, in the opinion of the attorney designated below for applicant(s), information relevant to the closest prior art of which that person is aware. The filing of this Information Disclosure Statement shall not be construed as a representation that a search has been made or that no other art than that identified exists.

<u>PATENT NO.</u>	<u>INVENTOR</u>	<u>ISSUE DATE</u>
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Alexander Starikov, *Exposure Monitor Structure* SPIE Integrated Circuit Metrology, Inspection, and Process Control IV, Vol 1261, 1990, pages 315-324

A copy of each of the foregoing items and Form PTO 1449 are enclosed herewith.

Respectfully submitted,

By:



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CERTIFICATE OF MAILING UNDER 37 CFR 1.10

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